

# **Technical Information Manual**

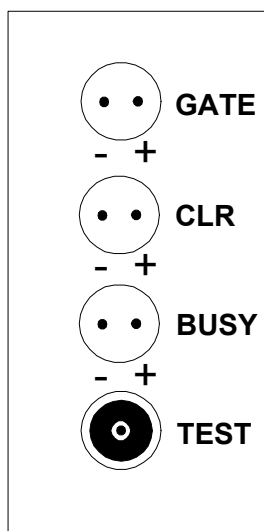
Revision n. 1

10 March 2003

**MOD. V 265**  
*8 CHANNEL  
CHARGE INTEGRATING  
ADC*



**N.B.: For Mod. V265E, the following picture shows the polarities of the GATE, CLEAR and BUSY signals on the couple of pins placed in replacement of the LEMO 00 type connectors.**





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# 1. Description

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## 1.1. Functional Description

The Model V 265 8 CHANNEL CHARGE INTEGRATING ADC is an A24-D16 single width VME Slave module provided with eight independent channels capable of converting the charge associated with an input signal to a 16-bit word.

For each channel, the input charge is converted to a voltage level by a Charge to Voltage Converter (CVC). The conversion process begins whenever a GATE input signal (NIM level) becomes TRUE, and it stops when the GATE signal becomes FALSE.

As soon as the GATE becomes FALSE, each CVC output voltage is sequentially transformed to a 16-bit word by two parallel 12-bit Analog to Digital Converters (ADC), and at the same time a BUSY output signal is available at the corresponding front panel connector. During the time interval in which the BUSY signal is active no GATE signal is accepted.

Each 16-bit word (containing the analog-to-digital conversion value, a channel identifier and an ADC RANGE identifier) is stored into a FIFO memory (Data Register readable via VME) capable of storing up to 16 events (i.e.:16\*8\*2 16-bit words). The current state (READY or FULL) of the FIFO memory is signalled by two dedicated front panel LEDs ("RDY" and "FULL") and can be known by reading the Status/Control Register via VME.

At the end of the analog-to-digital conversion of the last input signal, the BUSY signal is automatically deactivated and the module's CVCs are cleared: in this way further inputs can be converted.

The module (CVCs, internal registers and FIFO memory) can be cleared via VME or by a NIM level signal sent to the CLR front panel connector.

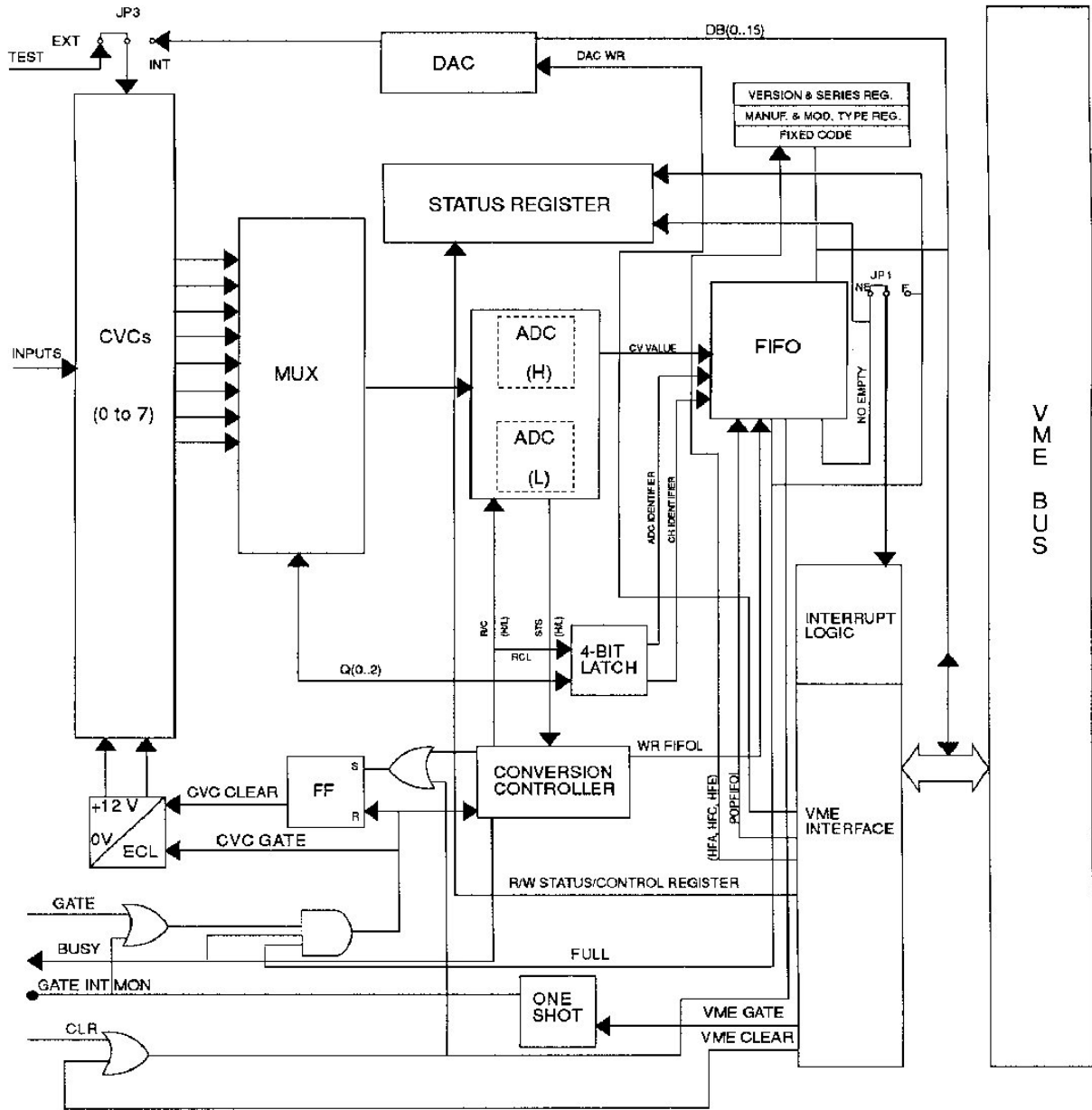
On the inside of the module a GATE generator and a DAC are present which allow the user to perform test operations via software.

The module's Base Address is settable through four rotary switches located on the printed circuit board.

This module exists in two versions:

Mod. V 265 E whose control signals (GATE, CLEAR, BUSY) are ECL differential

Mod. V 265 N whose control signals (GATE, CLEAR) are std. NIM level and the BUSY signal is open collector TTL level.



**Fig. 1.1 – Functional Block Diagram of the Module**



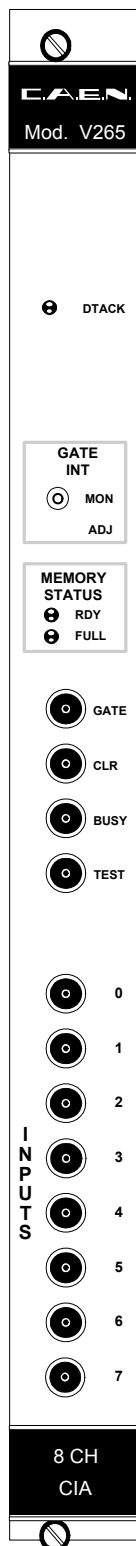


Fig. 1.2 – Mod. V265 Front panel

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## 2. Specifications

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### 2.1. Packaging

1-unit wide VME module.

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### 2.2. External components

#### CONNECTORS:

- No. 8 LEMO 00 type "INPUTS 0..7". Input connectors 0 to 7.
- No. 1 LEMO 00 type (or ECL type) "GATE". GATE signal input connector.
- No. 1 LEMO 00 type (or ECL type) "CLR". CLEAR signal input connector.
- No. 1 LEMO 00 type (or ECL type) "BUSY". BUSY signal output connector.
- No. 1 LEMO 00 type "TEST". TEST signal input connector.

#### DISPLAYS:

- No. 1 red LED "FULL". It lights up whenever the module's FIFO memory is full.
- No. 1 green LED "RDY". It lights up if the module's FIFO memory contains at least a valid datum.
- No. 1 red LED "DTACK". It lights up during a VME access.

#### TEST POINTS:

- No. 1 "GATE INT MON". Internal GATE monitoring.

#### TRIMMERS:

- No. 1 screw-driver trimmer "GATE INT ADJ". For the internal GATE width adjustment.

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### 2.3. Internal Components

#### FUSES:

- F1: +5 V, 5 A (trinitron type);
- F2: +12 V, 2 A (trinitron type);
- F3: -12 V, 2 A (trinitron type).

#### **JUMPERS:**

- JP1: a two-position jumper dedicated to the selection of the interrupt generation according to the FIFO memory state (NO EMPTY or FULL).
- JP2: a two-position jumper dedicated to the selection of an internal or external TEST signal.

#### **SWITCHES:**

- No. 4 rotary switches for the Module's Base Address selection.

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## **2.4. Characteristics of the signals**

#### **INPUTS:**

- signals to be converted (INPUTS 0 to 7): positive or negative polarity and AC/DC coupled on request. 50Ω impedance;
- GATE and CLEAR: V 265E: ECL differential 110 Ω impedance;  
V 265N: standard NIM level 50Ω impedance;
- TEST: same as the signals to be converted (negative polarity only).  
15K Ω impedance.

#### **OUTPUTS:**

- BUSY: V 265E: ECL differential.  
V 265N: TTL level, open collector, negative logic.
- GATE INT MON: ECL level, positive logic.

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## **2.5. Performances and test results**

- Input impedance: 50Ω ±1.5%.
- Input offset voltage: ± 2 mV.
- Input range: -1.5 V to +5 mV for linear response (negative input).
- Full scale: ≈120 pC (15 bits ADC range), ≈800 pC (12 bits ADC range).
- Conversion gain: ≈30 counts/pC (15 bit ADC range), ≈4 counts/pC (12 bit ADC range).
- Gain dispersion: ±2 counts/pC max.
- Gain variations versus relative timing input to GATE: 1.05%.
- Integral non linearity (see page 9): within ±7 counts (15 bit ADC range), ±2.5 counts (12 bit ADC range).
- Gate width: 100 ns to 5 μs.

- Gate timing: the GATE signal must precede the analog input by  $\geq 65$  ns.
- FAST CLEAR width:  $\geq 30$  ns. The pedestal settles with  $\pm 1$  count after 200 ns (12 bits).
- Conversion time: 300  $\mu$ s/8-ch.
- test sensitivity:  $\approx 30$  times less than a channel.
- Pedestal/GATE width:  $\approx 50$  counts/100 ns (15 bit ADC range),  $\approx 7$  counts/100 ns (12 bit ADC range).
- Residual pedestal:  $\approx 50$  counts (15 bit ADC range),  $\approx 7$  counts (12 bit ADC range) (for a GATE width of 300 ns and a high source impedance).
- Temperature coefficient: + 0.15% or + 3 counts/ $^{\circ}$ C max.
- RMS noise: negative input: 1 count (12 bit range), 2 counts (15 bit range); positive input: 1.3 counts (12 bit range), 6 counts (15 bit range).

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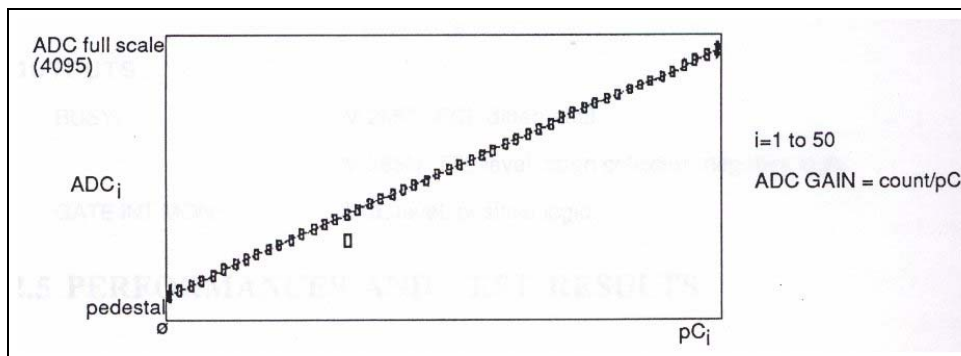
## 2.6. Power requirements

+ 5	2.62 A.
-12 V	25 mA.
+12 V	102 mA.

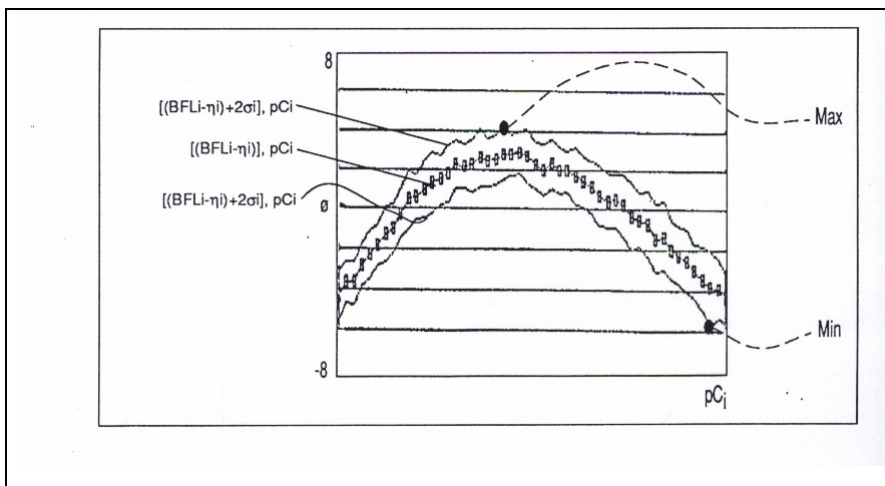
## 2.7. Integral non linearity test procedure performed by CAEN

### PROCEDURE

1. On the V 265 printed-circuit board, set the JP3 jumper to "INT" position: the module's internal DAC is enabled to supply the CVC inputs with an appropriate signal and an internal GATE signal can be generated (see 5 Test logic).
2. Set the GATE width to  $\approx 400$  ns.
3. By performing a WRITE operation, set the DAC register to an initial voltage value.
4. Read "i" ADC output values (where  $i = 1$  to 50) and calculate the corresponding  $\eta_i$  (medium value) and  $\sigma_i$  (standard deviation).
5. Increase the DAC voltage value and repeat the step 4.
6. Repeat step 5 until 50  $\eta_i$  and  $\sigma_i$  values are obtained.
7. Calculate the corresponding Best Fit Line (BFL):



8. Calculate the maximum value (Max) of  $[(BFL_i - \eta_i) + 2\sigma_i]$  and the minimum value (Min) of  $[(BFL_i - \eta_i) - 2\sigma_i]$  where  $i = 1$  to 50. The maximum integral non linearity value is:  $(Max - Min) / 2$



## 3. Operating mode

The Model V 265 is an A24-D16 VME slave and it can be operated in Data Space, User or Supervisor mode. Before using the module it is necessary to select the module's Base Address (in a range from 0000XXH to FFFFXXH) and on which condition of the internal FIFO memory a VME INTERRUPT will be generated. For this purpose, the module's printed circuit board is provided with four rotary switches (Base Address selection) and a jumper labelled "JP1" (see Fig. 3.1).

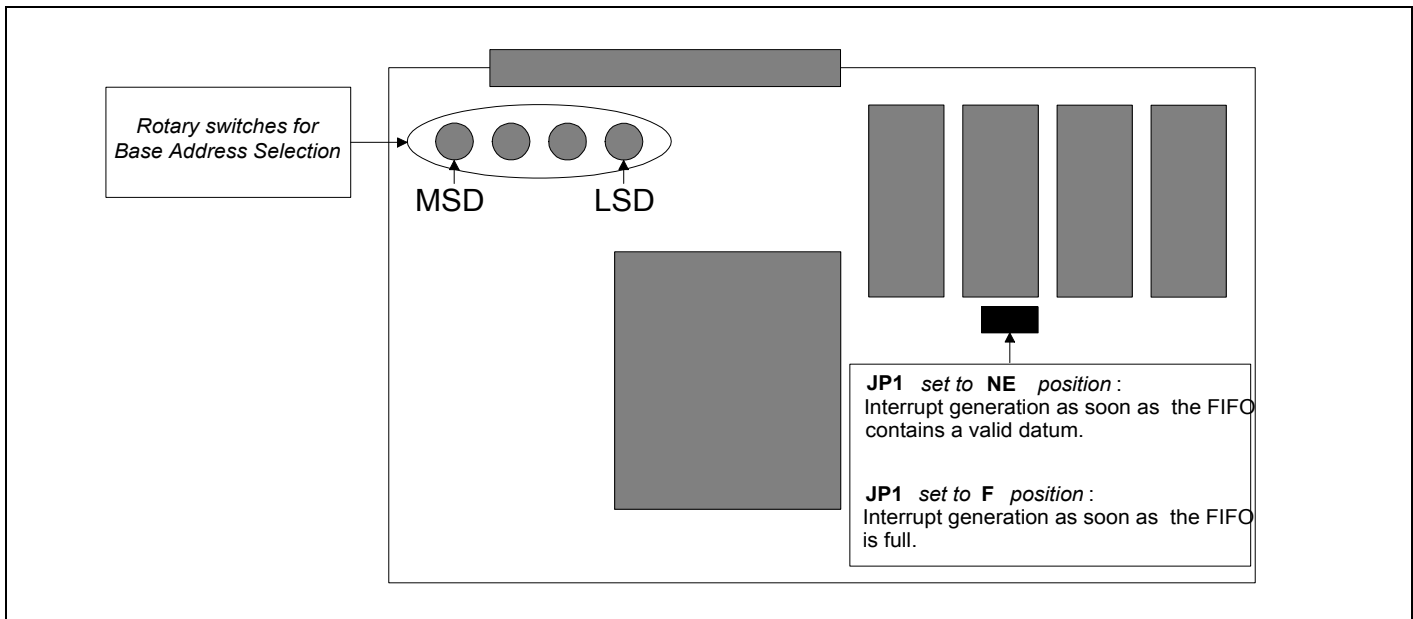


Fig. 3.1 – Rotary Switch and Jumper Position

### 3.1. Operations to be performed

**CAUTION:** Turn OFF the VME crate before inserting or removing the module.

1. By using the four rotary switches located on the module's printed circuit board, set the module's Base Address as required (0000XXH to FFFFXXH).
2. Set the **JP1** internal jumper as required (see Fig. 3.1).
3. Insert the module into a VME slot.
4. Turn ON the System.

THE MODULE IS READY TO BE OPERATED VIA VME (see Table 3.1 for the module's internal addresses specifications).

**Table 3.1 –Internal Address Specifications**

<b>BASE ADDRESS +</b>	<b>REGISTER/CONTENT</b>	<b>TYPE</b>	<b>EXPLANATION</b>
FEH	Version & Series	READ	This register contains the module's version and series number. Bits 15 to 12: Version (0000=NIM; 0001=ECL). Bits 11 to 0: Series number.
FCH	Manufacturer & Module's Type	READ	This register contains the binary codes corresponding to the module's manufacturer and model. Bits 15 to 10: Manufacturer code (CAEN=000010). Bits 9 to 0: Module Code (V265=0000010010).
FAH	Fixed Code	READ	HF5 code
F8H to 0AH	UNUSED	///	////
08H	Data Register	READ	This register contains a channel number, an ADC number and the converted value correlated with the channel itself. Bits 15 to 13: channel number. Bit 12: 0→12 bit ADC range 1→15 bit ADC range Bits 11 to 0: converted value (the read value is valid if RDY bit of the Status/Control Register is equal to 1[see Table 3.2]).
06H	Gate Generation	READ/WRITE	An R/W operation generates an internal GATE signal. The GATE width can be set by the GATE INT ADJ trimmer located on the module's front panel and it can be monitored by an oscilloscope connected with the GATE INT MON test point (ECL signal, positive logic).
04H	DAC Register	WRITE	Internal DAC setting (see 5 Test logic).
02H	Clear	READ/WRITE	An R/W operation resets the module (the CVCs and the internal registers are initialized and the FIFO memory is cleared) The same result can be obtained by sending a NIM level signal to the CLR front panel connector.
00H	Status/Control Register	READ/WRITE	See Table 3.2



**Table 3.2 –Status/Control Register Configuration**

<b>BIT</b>	<b>CONTENT</b>	<b>TYPE</b>
15	RDY (RDY=1 if FIFO=no empty)	READ
14	FULL (FULL=1 if FIFO=full)	READ
13 to 11	UNUSED	
10 to 8	INTERRUPT Level 000=INTERRUPT disabled (001 to 111)=INTERRUPT levels	READ/WRITE
7 to 0	INTERRUPT Vector According to the JP1 position, an INTERRUPT can be generated either when the FIFO memory is no empty or when the FIFO itself is full. The INTERRUPT is RORA (Reset On Register Access) type and it is reset whenever the RUDY or FULL bit (according to the JP1 position) of the Status/Control Register becomes FALSE.	READ/WRITE

## 3.2. Software programs example

### FIFO MANAGEMENT IN POLLING MODE:

```

program read_ADC;
const
    STS_REG=Base Addr+00H;
    DATA_REG=Base Addr+08H;
var
    STATE,RDY,i: integer;
    buffer: array[1..16] of integer;
begin
    i:=1;
    repeat
        repeat
            STATE:=memread(STS_REG);
            RDY:=STATE and 8000H
        until(RDY=8000H);           {RDY test}
        buffer[i]=memread(DATA_REG); {data read}
        i:=i+1;
    until (i=16);                 {buffer=full}
    writeln('One event has been acquired');
end.
```

### INTERRUPT MANAGEMENT:

```

program read_ADC_INT;
const
    STS_REG=BaseAddr+00H;
    DATA_REG=Base Addr+08H;
var
    STATE,RDY,i: integer;
    buffer: array[1..16] of integer;
    INT_FLAG: boolean;

procedure INT_DRV;           {INTERRUPT driver}
begin
    i:=1;
    DIS_INT;                  {INTERRUPT level set to 0}
    repeat
        repeat
            STATE:=memread(STS_REG);
            RDY:=STATE and 8000H
        until(RDY=8000H);     {RDY test}
        buffer[i]=memread(DATA_REG); {data read}
        i:=i+1
    until (i=16);            {buffer=full}
    INT_FLAG:=true;
end;

begin                         {Main Program}
    INT_FLAG:=false;
    INIT;                       {Initialize INTERRUPT vector and level}
INTERRUPT
    repeat
        if INT_FLAG then      {INTERRUPT waiting}
            begin
                <data storage>
                INT_FLAG:=false; {flag recovery}
                EN_INT           {INTERRUPT level recovery}
            end;
        .
        .
    until false;
end.
```

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## 4. Calibration operations

The operations to be performed to calibrate the module are listed in the following paragraph 4.2. As an example we have used the V 265 N version.

The module must be inserted into a VME slot and the system has to be power supplied.

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### 4.1. Necessary instruments

- No. 1 Pulse Generator capable of producing standard NIM (or ECL) level signals.
- No. 1 Voltmeter.
- No. 1 Oscilloscope.

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### 4.2. Operations to be performed

#### 1. GATEH AND CLEARH LEVEL ADJUSTMENT

Via Pulse Generator, send a 1  $\mu$  s wide NIM pulse to the GATE connector and a 300 ns wide NIM pulse to the CLR connector according to the timing diagram (see Fig. 4.2).

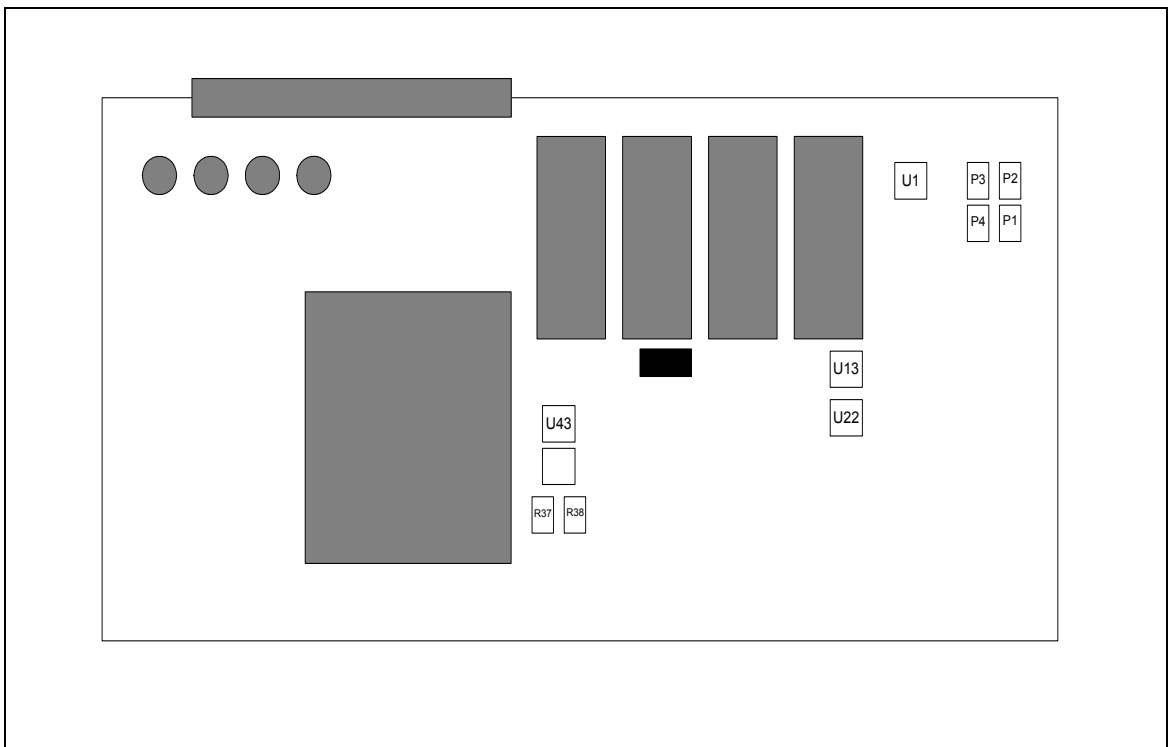
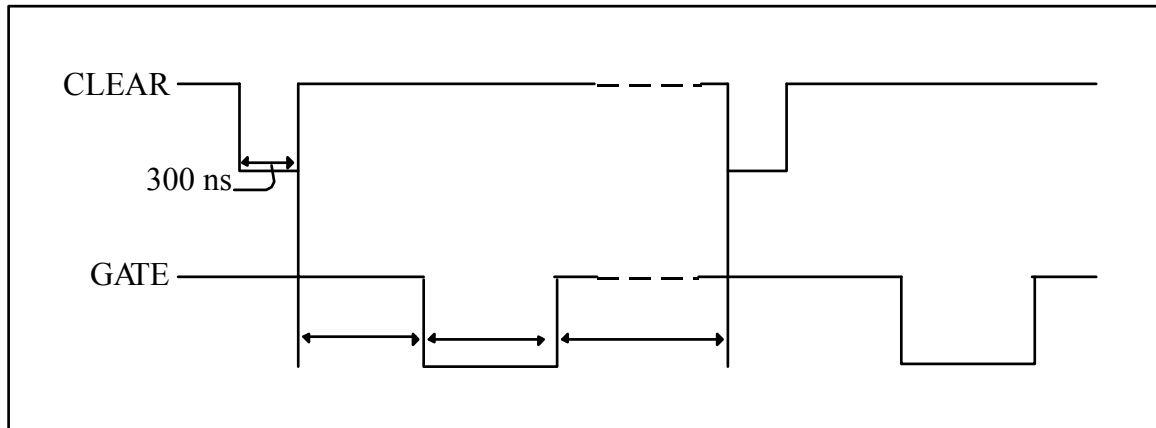


Fig. 4.1 – Internal Trimmers

On the piggy-back card, turn the P1 trimmer until a signal which has about the same GATE signal width, but that switches between 0 and +12/13 Volt, is obtained.



**Fig. 4.2 – Timing Diagram**

## **2. U13 OFFSET ADJUSTMENT**

Supply the CLR input with a NIM level signal ( $-800$  mV). Connect the voltmeter to U13 - pin 6 and U13 - pin 3. Turn the P1 trimmer located on the printed circuit board until the voltage value shown on the voltmeter is equal to zero.

## **3. U22 OFFSET ADJUSTMENT**

Supply the CLR input with a NIM level signal ( $-800$  mV). Connect the voltmeter to U22 - pin 6 and to ground. Turn the P2 trimmer until the voltage value shown on the voltmeter is equal to zero.

## **4. U1 OFFSET ADJUSTMENT**

Supply the CLR input with a NIM level signal ( $-800$  mV). Connect the voltmeter to U1 - pin 6 and to ground. Turn the P3 trimmer until the voltage value shown on the voltmeter is equal to zero.

## **5. PEDESTAL ADJUSTMENT**

Via Pulse Generator send a  $1 \mu\text{s}$  wide NIM pulse to the GATE connector. Read the ADC1 conversion value and turn the P4 trimmer until the read value is  $\approx 75$ . The pedestal is now set to  $\approx 7.5$  counts/100 ns (12 bit ADC range).

## **6. DAC OFFSET ADJUSTMENT**

Load the module's DAC with 000H. Connect the voltmeter to U43 - pin 6 and to ground. Turn the R38 trimmer until the voltage value shown on the voltmeter is equal to zero.

## **7. DAC FULL SCALE ADJUSTMENT**

Load the module's DAC with FFFH. Connect the voltmeter to U43 - pin 6 and to ground. Turn the R37 trimmer until the voltage value shown on the voltmeter is equal to  $-9$  V .

## 5. Test logic

The module is provided with a test circuitry capable of producing an internal GATE signal via software by performing an R/W operation addressed to the Base Address+06H module's location. The internal GATE width is adjustable (through the front panel trimmer GATE INT ADJ) in a range from 400 ns to 2  $\mu$ s, and it can be monitored by an oscilloscope connected to the GATE INT MON test point (ECL level, positive logic).

A 12-bit DAC supplies the CVC inputs with an appropriate signal according to the following formula:

$$Q \cong ((9 \times TGATE) \div (15000 \times 4095)) \times DAC$$

Where **Q**=INPUT CHARGE (Coulomb), **TGATE**=internal GATE width (seconds) and **DAC**=binary code of the voltage value set to the DAC Register by a WRITE operation.

The DAC Register content generates a voltage value according to the following formula:

$$V = (9 \div 4095) \times DAC$$

where DAC can vary in a range from 0 to 4095. Instead of using the internal DAC, it is also possible to supply the CVC inputs with a common charge through the front panel connector TEST. An internal jumper (JP3) allows the user to select the required operating mode (see Fig. 5.1)

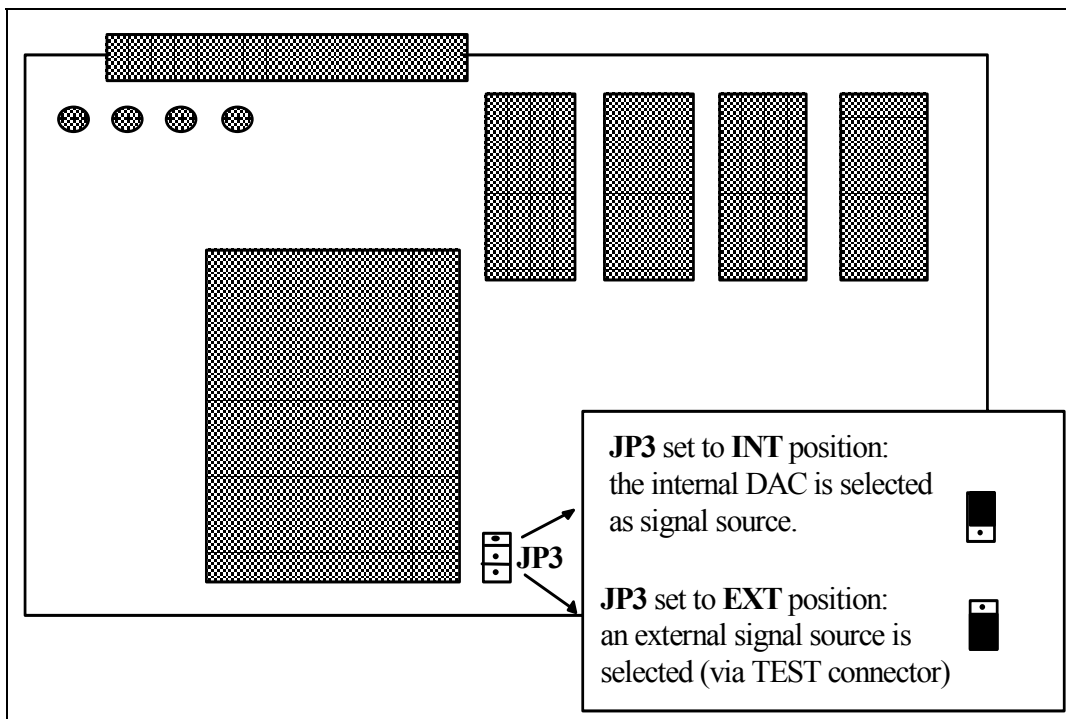


Fig. 5.1 – Internal Jumper J3 position